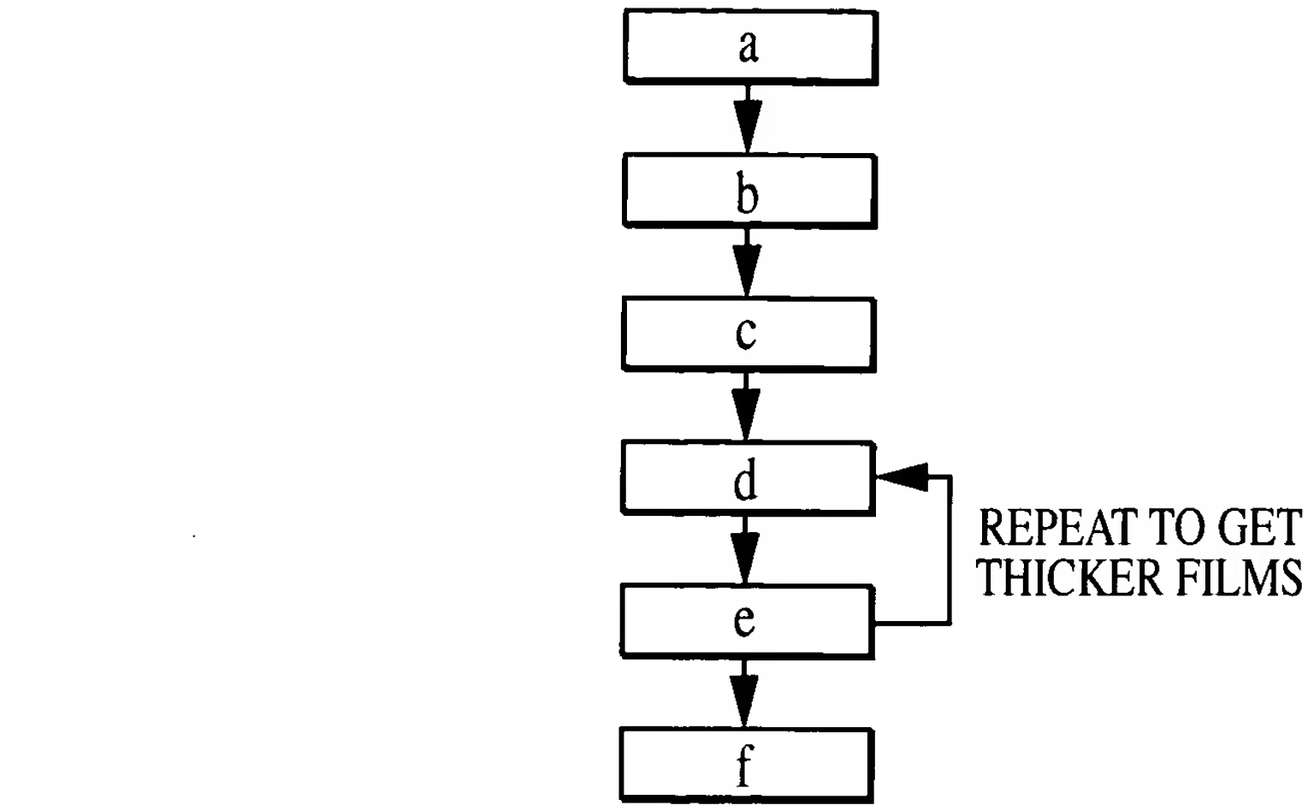

FIG. 1

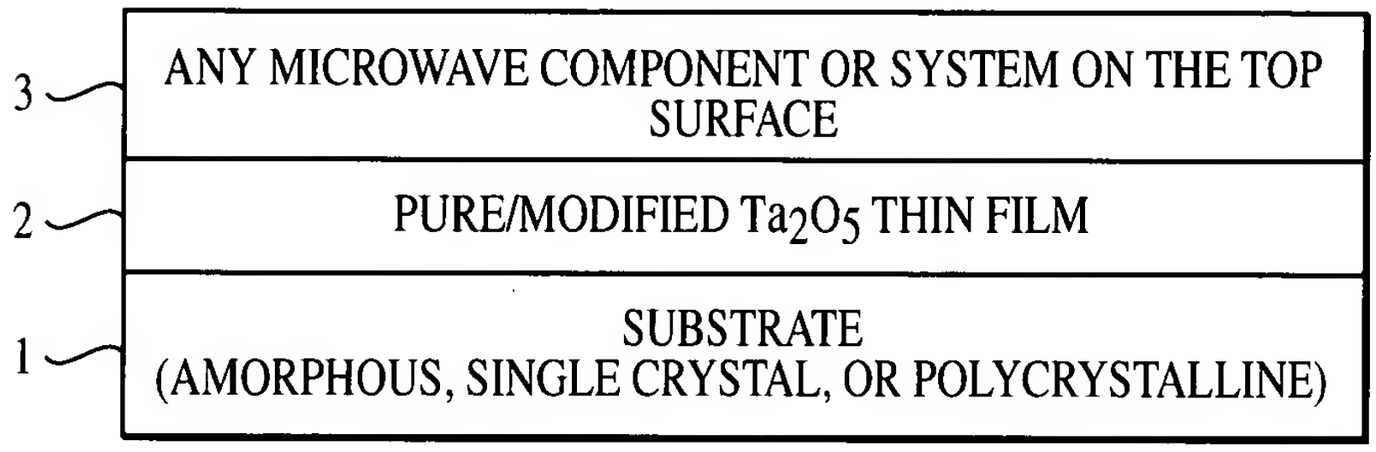

FIG. 2(a)

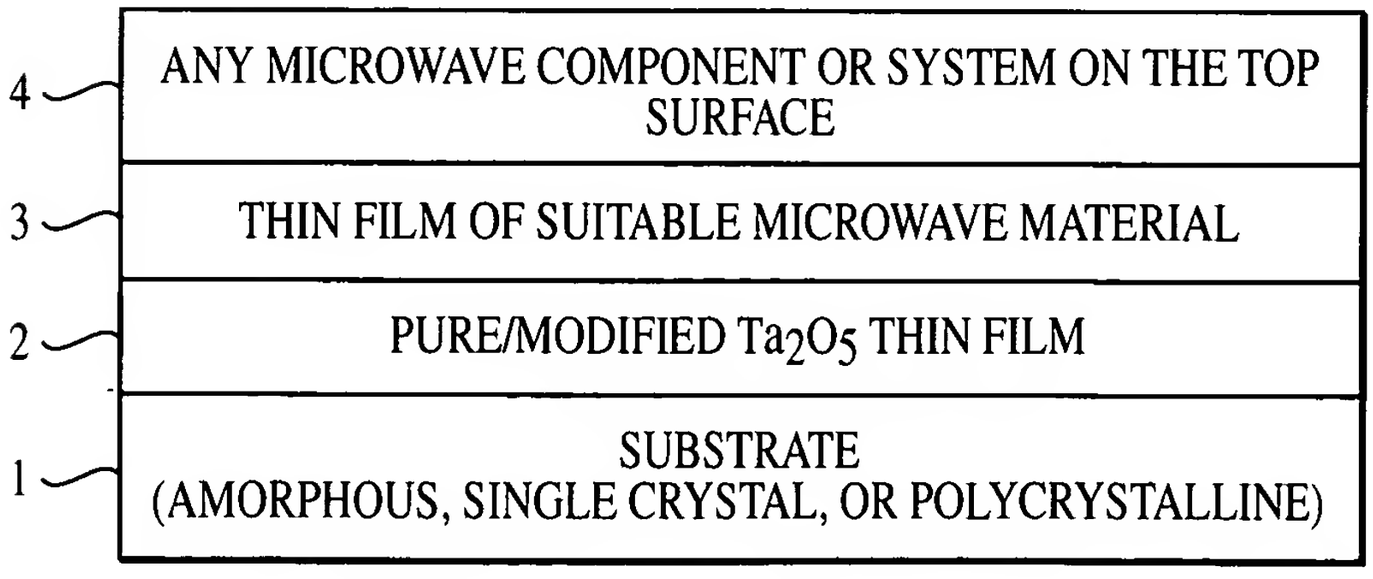

FIG. 2(b)

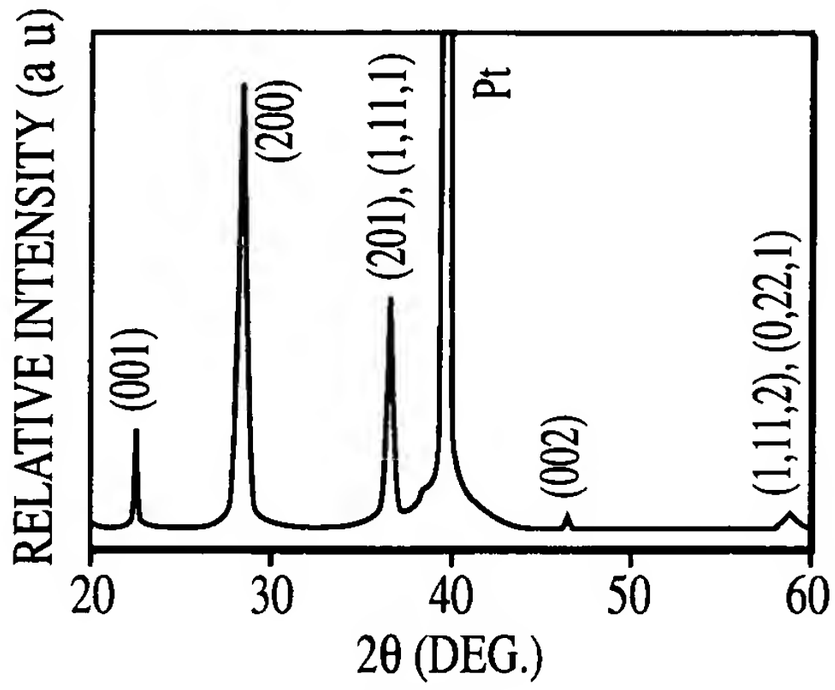

FIG. 3

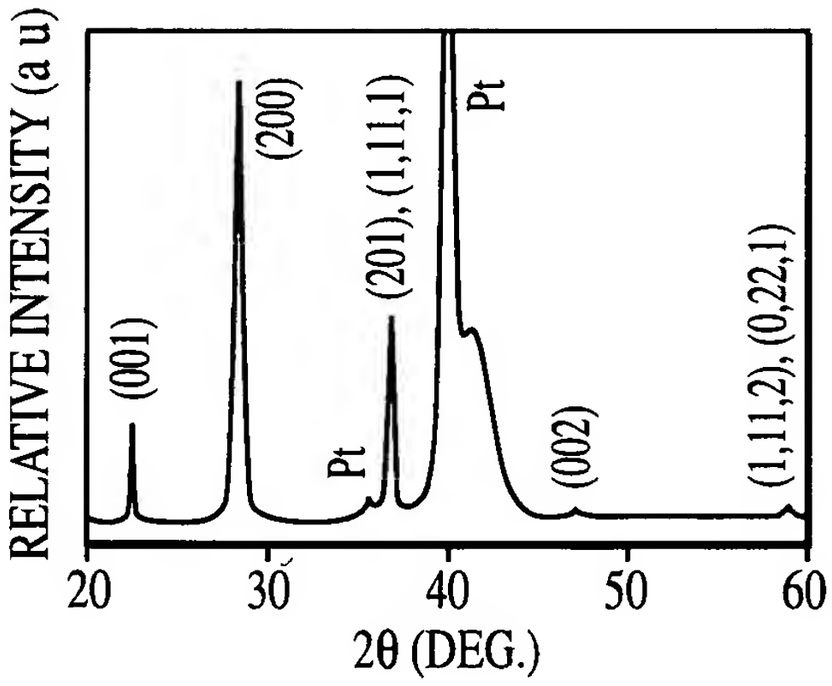

FIG. 4

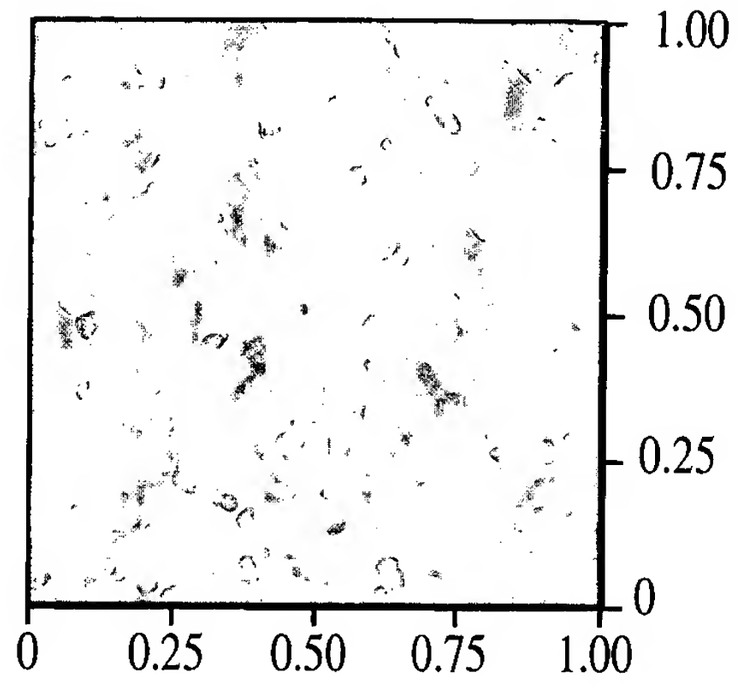

FIG. 5

$0.9Ta_2O_5$-$0.1Al_2O_3$ THIN FILMS	
DIELECTRIC CONSTANT	42.8
DISSIPATION FACTOR	0.005
CHARGE STORAGE DENSITY	18.9 fC/μm^2 (AT 0.5 MV/cm)
LEAKAGE CURRENT DENSITY	$<10^{-9}$ A/cm^2 (AT 0.5 MV/cm)
TEMPERATURE COEFFICIENT OF CAPACITANCE	-20 ppm/°C (RANGE 25-125 °C)
BIAS STABILITY OF CAPACITANCE	0.4% (UP to 1 MV/cm)

FIG. 6